Precision Equation-of-State (EOS) Measurements Using Laser-Driven Shock Waves On the OMEGA Laser



M. A. Barrios University of Rochester Laboratory for Laser Energetics Omega Laser Facility Users' Group Workshop Rochester, NY 29 April – 1 May 2009 Summary

Precision equation-of-state (EOS) measurements are obtained using quartz as a standard

- The impedance-matching (IM) technique has been used for decades to obtain EOS measurements, mainly using opaque standards.
- Both random and systematic errors, inherent in IM, must be addressed.
- Transparent standards (quartz) allow one to measure the shock velocity (U_s) within the standard, reducing random errors.
- This high-precision technique was applied to CH and CH₂.



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EOS Measurements

Laser-driven shocks are used to study materials at high pressure



Rankine–Hugoniot equations $\rho_0 U_s = \rho_1 (U_s - U_p)$ $P_1 - P_0 = \rho_0 U_s U_p$

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Laboratory frame position

The measurement of two variables is needed to close these equations; e.g., $U_s = F(U_p)$.

Impedance Match $U_s = F(U_p)$

The particle velocity and pressure are conserved across a contact interface



Need to minimize experimental error and address systematic errors for precision EOS measurements



 Measurement accuracy depends on knowledge of standard.

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- Most IM studies quote only random errors.
- Cannot propagate systematic errors using theoretical EOS.

• Random errors

$$\frac{\delta\rho}{\rho} \simeq (\eta - 1), \ \eta = \frac{\rho}{\rho_0}; \ \eta \simeq 4 - 6 \rightarrow \frac{\delta\rho}{\rho} \propto (3 - 5) \times \delta u_s$$

At high pressures inconsistencies exist between EOS models and data for aluminum



Random Errors

Higher precision is achieved using a transparent standard



Quartz validity as a standard is established through ample study of its EOS and agreement with previous results



D. G. Hicks et al., Phys. Plasmas E17325 <u>12</u>, 082702 (2005).

¹M. D. Knudson *et al.*, J. Appl. Phys. <u>97</u>, 073514 (2005).

²T. R. Boehly et al., in Shock Compression of Conducted Matter–2007, Vol. 955, p 19–22.

Precision EOS data more tightly constrain polystyrene (CH) EOS



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Precision EOS data more tightly constrain polystyrene (CH) EOS and polypropylene (CH₂) EOS



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